

**ABSTRACT OF THE DISCLOSURE**

**[0055]** A method and apparatus are disclosed for enabling reconfiguration of a test system. The test system includes an adapter assembly (106) and a tester electronics assembly (108). The adapter assembly (106) includes two probe plates (200, 202), which hold a probe field (116). The two probe plates (200, 202) include a plurality of holes (208) extending through each probe plate (116). Each hole (208) includes a flange area (206) for accommodating deflection of the probes (204), inserted in the holes (208) extending through the probe plates (200, 202). The flange area (206) and the use of flexible probes (204) facilitate a deflection and an offset (210) of the probes (204) in the probe plates (200, 202). A tester assembly (300) includes a plurality of wear pads (308) on the topside of a printed circuit board (302). The wear pads (308) positioned to engage the bottom end of the probes (204). Configurable logic elements (304) located on the underside of the printed circuit board (302) are used to generating and receive test-signals, depending on where the probes make contact with the wear pads (308) on the printed circuit board (302).